

N-Channel Enhancement Mode MOSFET

1. Product Information

1.1 Features

- ☒ Surface-mounted package
- ☒ Advanced trench cell design
- ☒ Super Trench
- ☒ MSL1

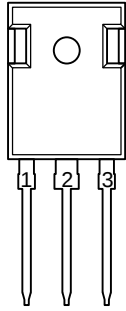
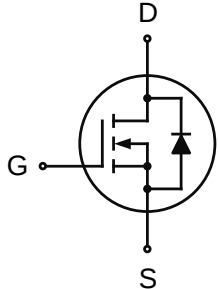
1.2 Applications

- ☒ BMS appliance
- ☒ High power inverter system
- ☒ Drones
- ☒ Light electric vehicles

1.3 Quick reference

- ☒ $BV \geq 85V$
- ☒ $R_{DS(ON)} \leq 1.7m\Omega @ V_{GS} = 10V$
- ☒ $P_{tot} \leq 500W$
- ☒ $I_D \leq 300A$

2. Pin Description

Pin	Description	Simplified Outline	Symbol
1	Gate(G)	 Top View TO-247	
2	Drain(D)		
3	Source(S)		

3. Limiting Values

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	Drain-Source Voltage	T _C =25°C	85	-	V
V _{GS}	Gate-Source Voltage	T _C =25°C	-	±20	V
I _D	Drain Current (DC)	T _C =25°C, V _{GS} =10V	-	300	A
I _D	Drain Current (DC)	T _C =100°C, V _{GS} =10V	-	267	A
I _{DM} *	Drain Current (Pulsed)	T _C =25°C, V _{GS} =10V	-	1200	A
P _{tot}	Drain Power Dissipation	T _C =25°C	-	500	W
T _{stg}	Storage Temperature		-55	150	°C
T _J	Junction Temperature		-	150	°C
I _S	Continuous-Source Current	T _C =25°C	-	300	A
E _{AS}	Single Pulsed Avalanche Energy	V _{DD} =40V, L=0.5mH	-	2800	mJ
R _{θJA} **	Thermal Resistance-Junction to Ambient		-	32.8	°C/W
R _{θJC} **	Thermal Resistance-Junction to Case		-	0.45	°C/W

Notes:

- * Pulse width ≤ 300μs, duty cycle ≤ 2%
- ** Surface Mounted on minimum footprint pad area
- *** Limited by bonding wire

4. Marking Information

Product Name	Marking
KJ4368P	KJ4368P YWWWXX YWWWX: Date Code

5. Ordering Code

Product Name	Package	Reel Size	Tape width	Quantity	Note
KJ4368P	TO-247	-	-	600	

Note: KUAIJIE XIN defines “Green” as lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900 ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500 ppm by weight; Follow IEC 61249-2-21 and IPC/JEDEC J-STD-020C)

6. Electrical Characteristics (T_A=25°C Unless Otherwise Noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250μA	85	95	-	V
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	2	-	4	V
I _{DSS}	Drain Leakage Current	V _{DS} =80V, V _{GS} =0V	-	-	1	μA
I _{GSS}	Gate Leakage Current	V _{GS} =0V, V _{GS} =±20V	-	-	±100	nA
R _{DS(ON)} ^a	On-State Resistance	V _{GS} =10V, I _{DS} =50A	-	1.5	1.7	mΩ
Diode Characteristics						
V _{SD} ^a	Diode Forward Voltage	I _{SD} =50A, V _{GS} =0V	-	-	1.2	V
t _{rr}	Reverse Recovery Time	I _{DS} =50A, V _{GS} =0V di _{SD} /dt=100A/μs	-	120	-	ns
Q _{rr}	Reverse Recovery Charge		-	360	-	nC
Dynamic Characteristics ^b						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =50V, Frequency=1MHz	-	14490	-	pF
C _{oss}	Output Capacitance		-	2350	-	
C _{rss}	Reverse Transfer Capacitance		-	472	-	
t _{d(on)}	Turn-on Delay Time	V _{DS} =50V, V _{GEN} =10V, R _G =4.5Ω, R _L =1Ω, I _{DS} =50A	-	39	-	ns
t _r	Turn-on Rise Time		-	122	-	
t _{d(off)}	Turn-off Delay Time		-	115	-	
t _f	Turn-off Fall Time		-	137	-	
Gate Charge Characteristics ^b						
Q _g	Total Gate Charge	V _{DS} =50V, V _{GS} =10V, I _{DS} =50A	-	240	-	nC
Q _{gs}	Gate-Source Charge		-	56	-	
Q _{gd}	Gate-Drain Charge		-	60	-	

Notes:

a: Pulse test; Pulse width ≤ 300μs, duty cycle ≤ 2%

b: Guaranteed by design, not subject to production testing

7. Typical Characteristics

Figure 1. Maximum Continuous Drain Current vs Case Temperature

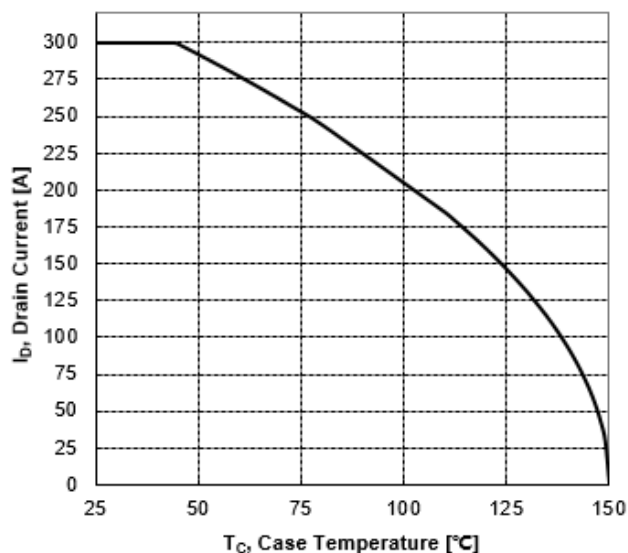


Figure 2. Typical Output Characteristics

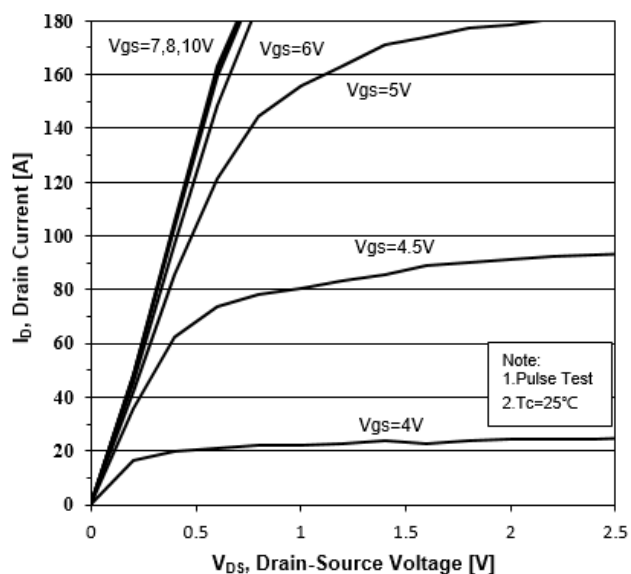


Figure 3. Typical Transfer Characteristics

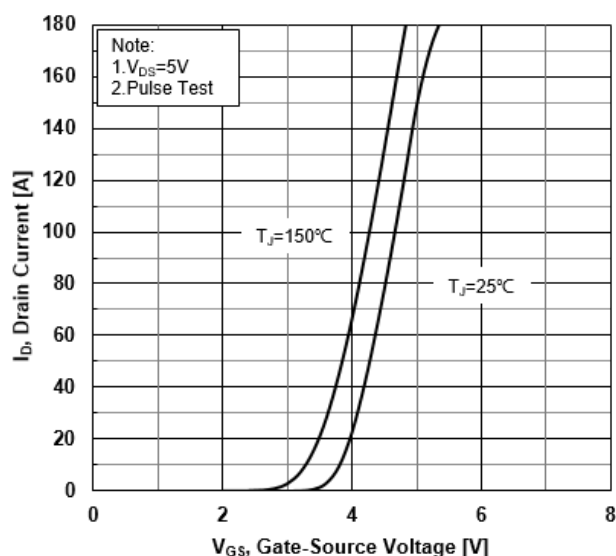
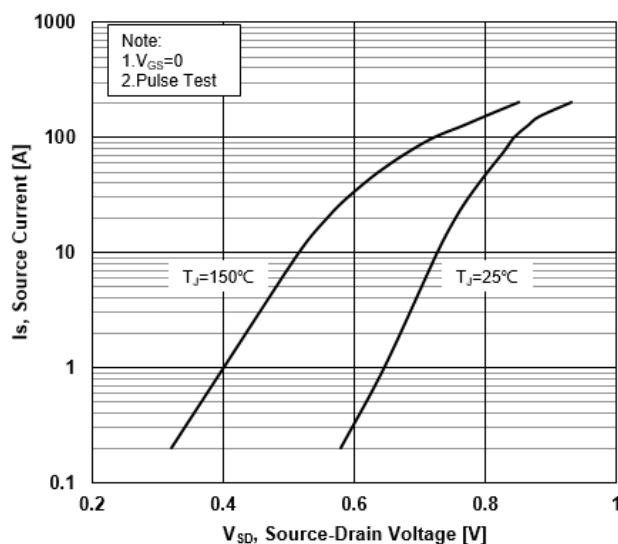


Figure 4. Source-Drain Diode Forward Characteristics



7. Typical Characteristics (cont.)

Figure 5. Drain-Source On-Resistance vs Drain Current

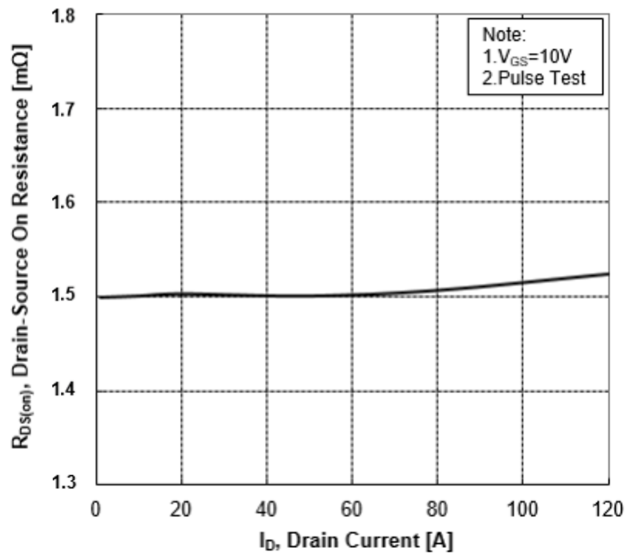


Figure 6. Normalized On-Resistance vs Junction Temperature

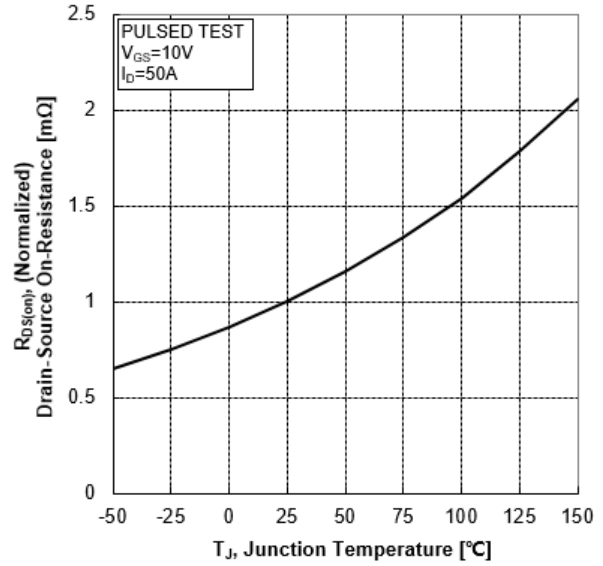


Figure 7. Normalized Threshold Voltage vs Junction Temperature

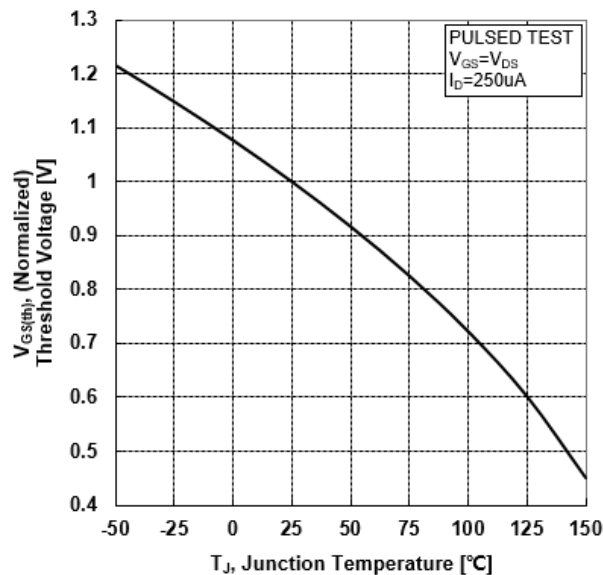
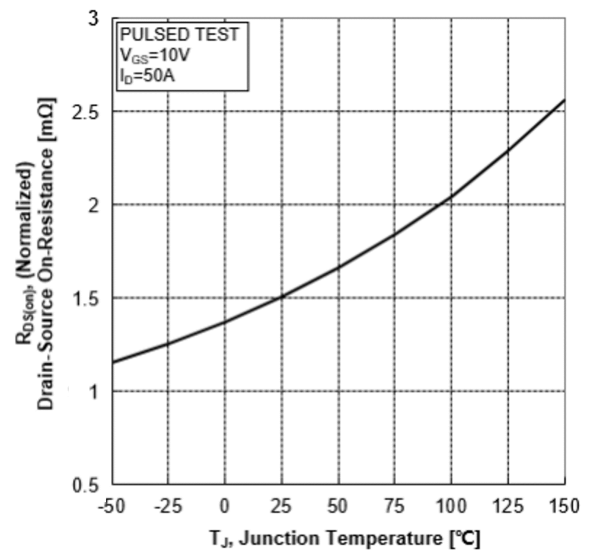
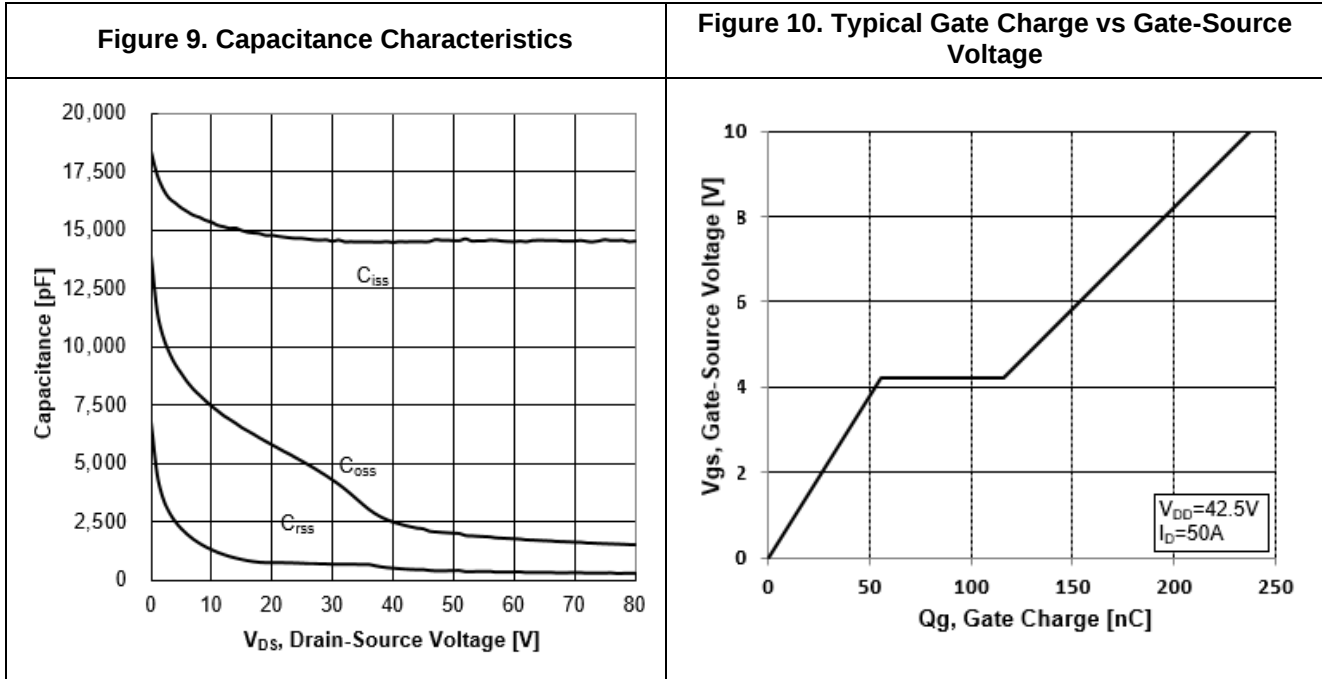


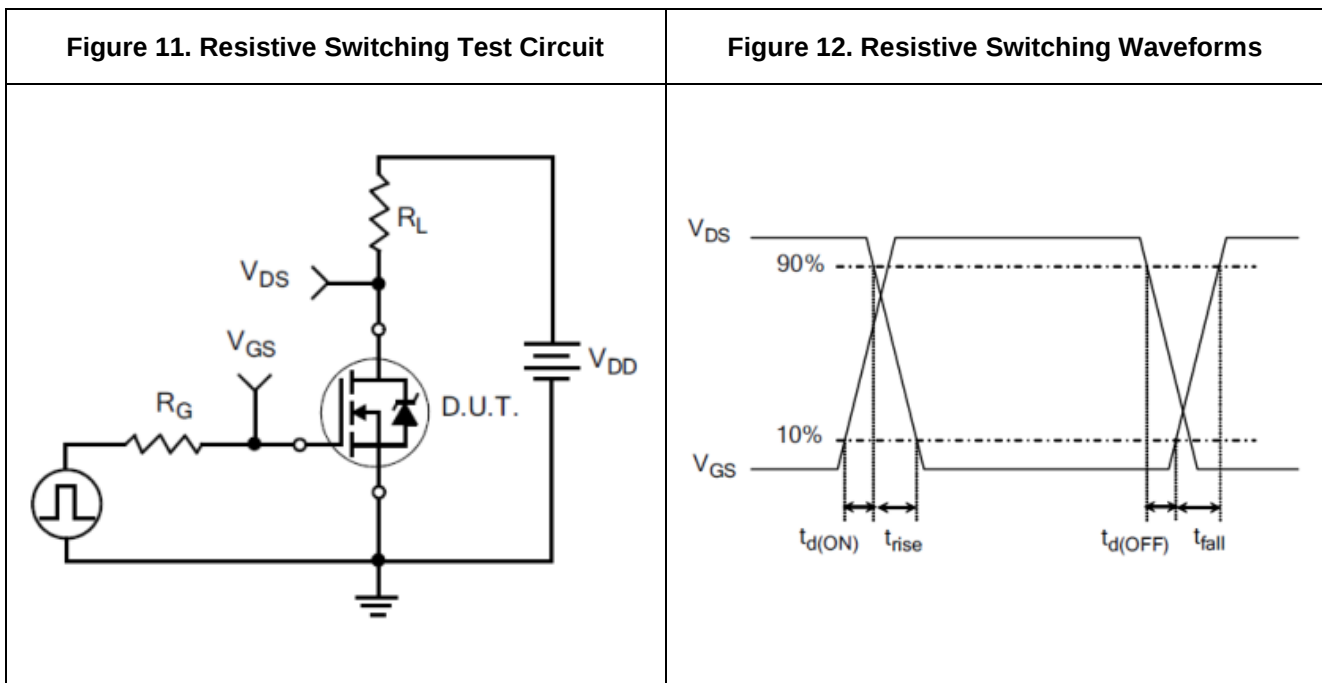
Figure 8. Normalized Breakdown Voltage vs Junction Temperature



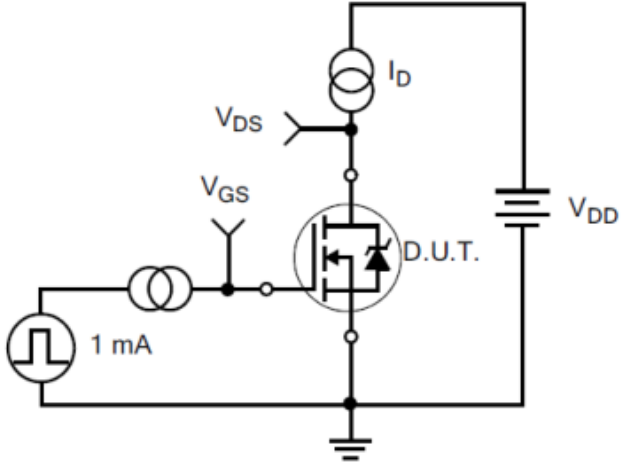
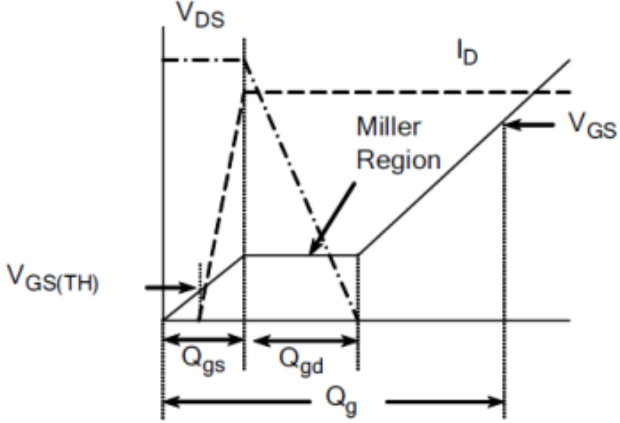
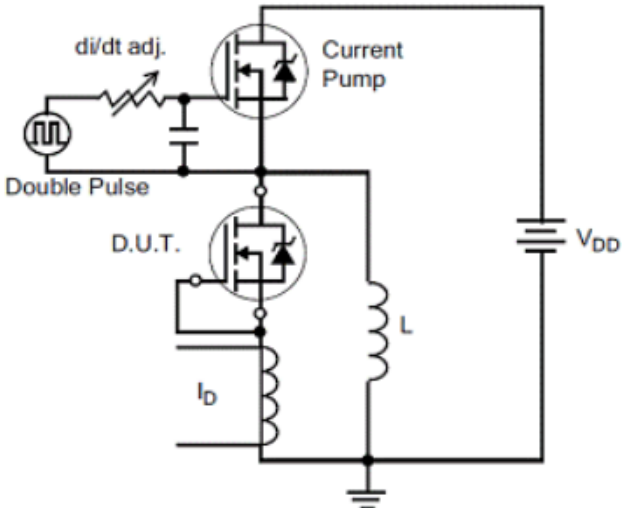
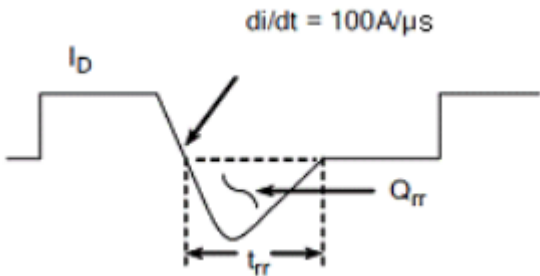
7. Typical Characteristics (cont.)



8. Test Circuit and Waveform



8. Test Circuit and Waveform (cont.)

Figure 13. Gate Charge Test Circuit	Figure 14. Gate Charge Waveforms
	
Figure 15. Diode Reverse Recovery Test Circuit	Figure 16. Diode Reverse Recovery Waveform
	

8. Test Circuit and Waveform (cont.)

Figure 17. Unclamped Inductive Switching Test Circuit

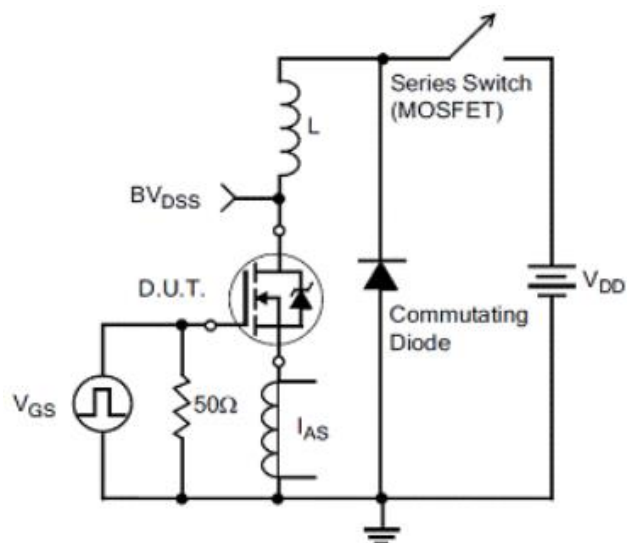
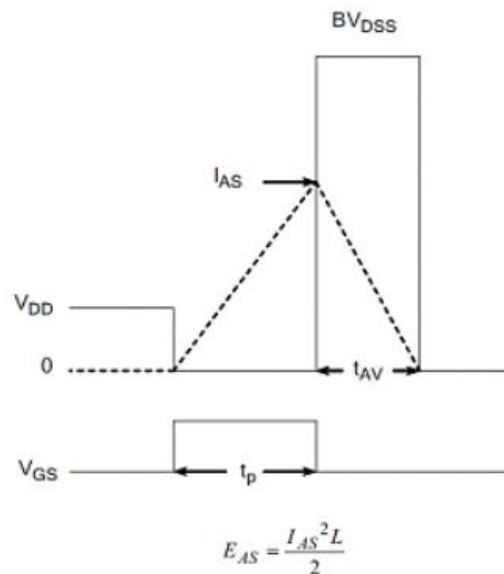
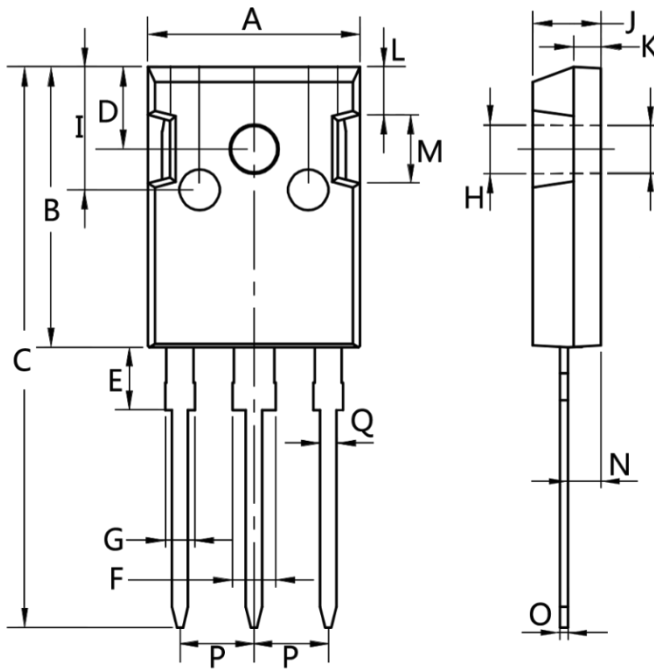


Figure 18. Unclamped Inductive Switching Waveform



9. Package Dimensions

TO-247 Package



Dim.	Min.	Max.
A	15.0	16.0
B	20.0	21.0
C	41.0	42.0
D	5.0	6.0
E	4.0	5.0
F	2.5	3.5
G	1.75	2.5
H	3.0	3.5
I	8.0	10.0
J	4.9	5.1
K	1.9	2.1
J	4.9	5.1
K	1.9	2.1
L	3.5	4.0
M	4.75	5.25
N	2.0	3.0
O	0.55	0.75
P	Typ 5.08	
Q	1.2	1.3